

**PATENT APPLICATION**  
**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Docket No: Q91474

Hideyuki OHTAKE, et al.

Allowed: August 8, 2008

Appln. No.: 10/569,796

Group Art Unit: 2829

Confirmation No.: 6630

Examiner: Richard Isla RODAS

Filed: February 27, 2006

For: ELECTRIC-FIELD DISTRIBUTION MEASUREMENT METHOD AND APPARATUS  
FOR SEMICONDUCTOR DEVICE

**AMENDMENT UNDER 37 C.F.R. §1.312**

**MAIL STOP ISSUE FEE**

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 C.F.R. §1.312, please amend the above-identified  
application as follows on the accompanying pages.

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